



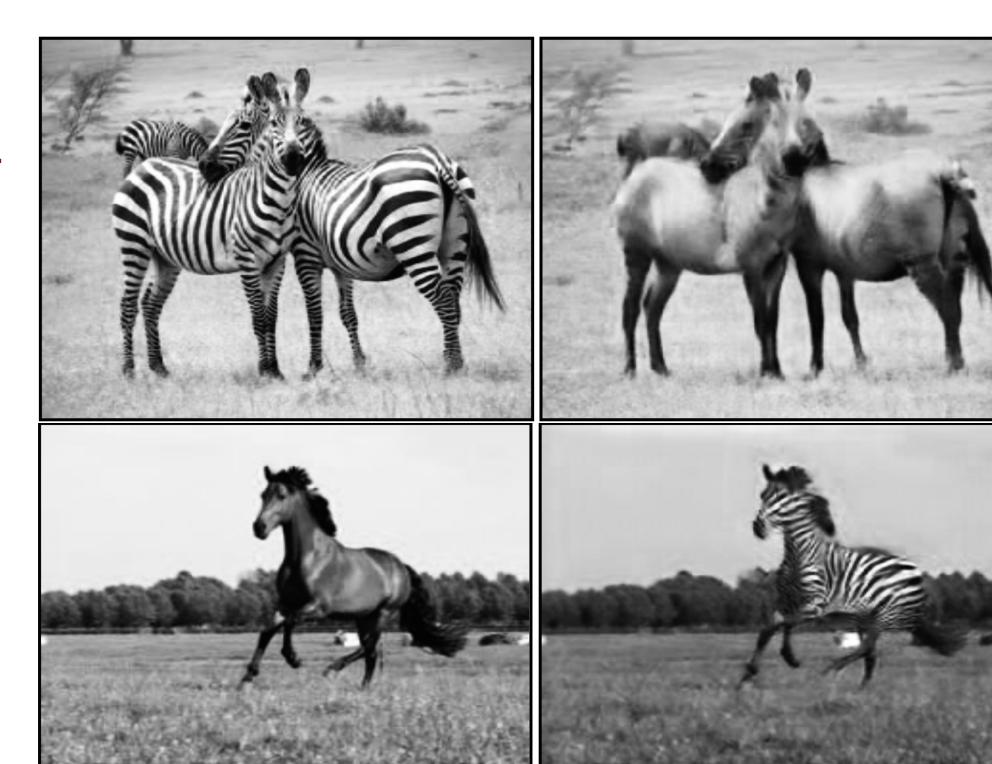
# Enhancing AFM Image Analysis Through Machine Learning with Style Translation and Data Augmentation

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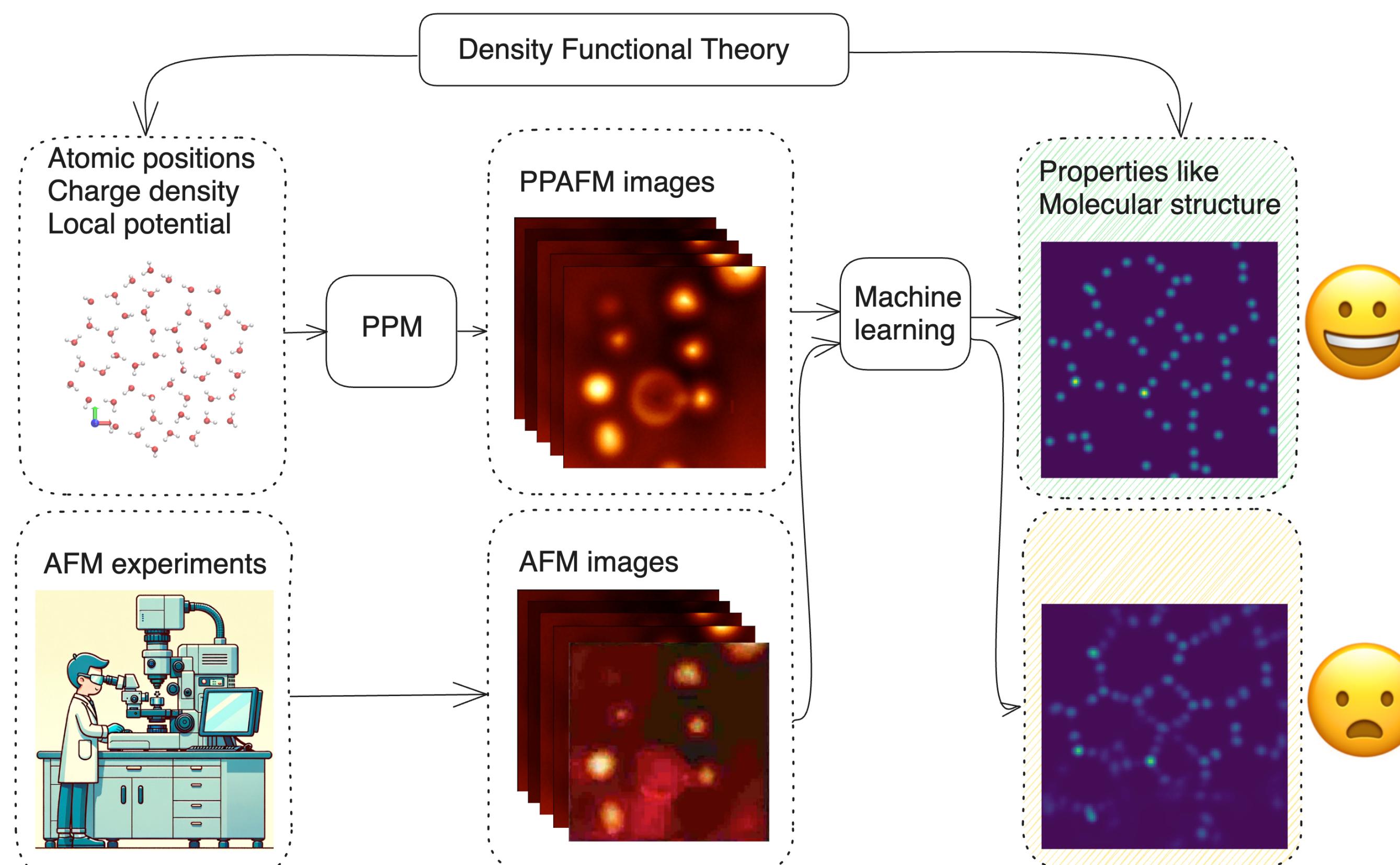
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## Introduction

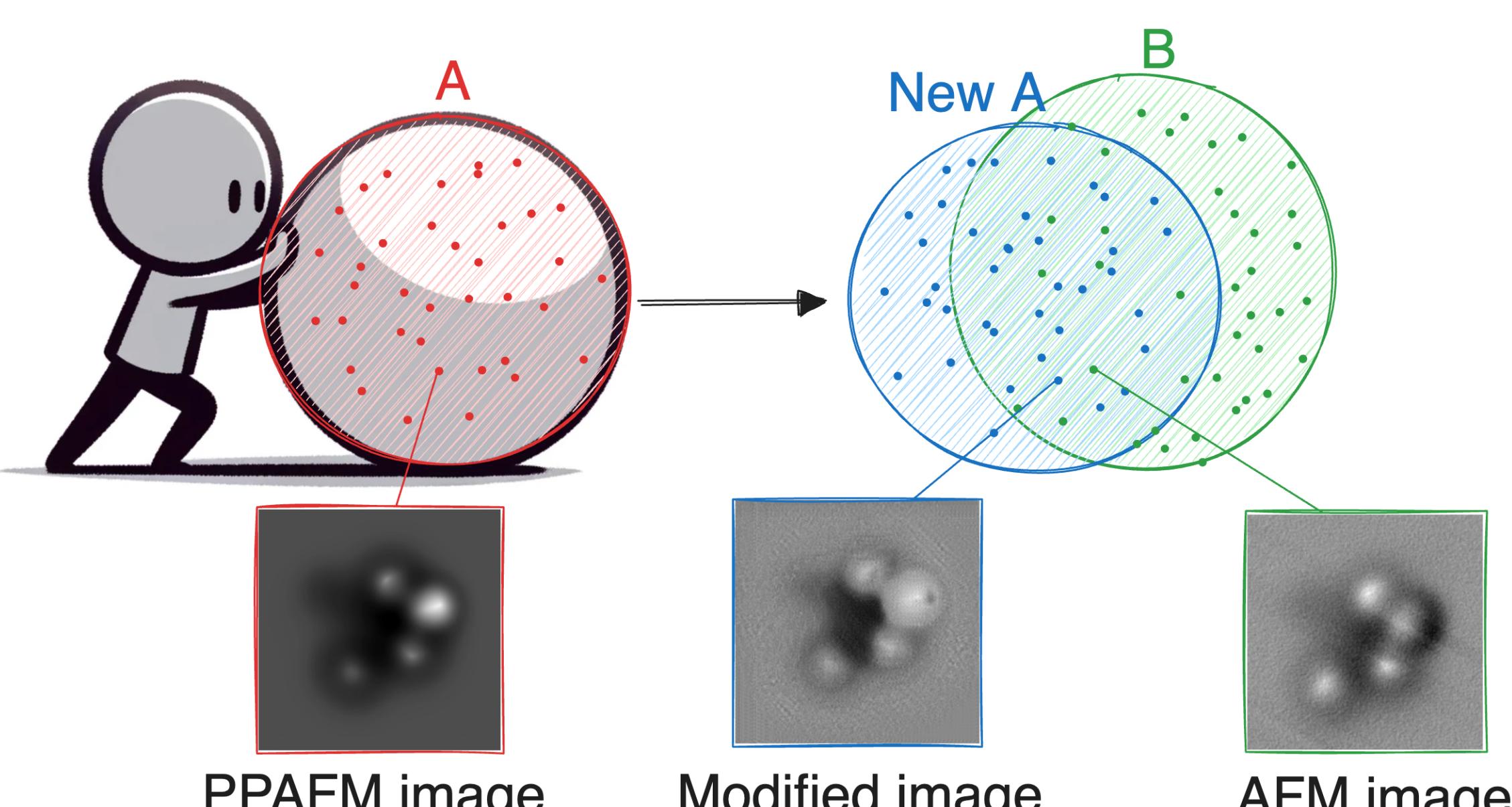
Atomic Force Microscopy (AFM) plays a crucial role in characterizing nano-structures. The Probe Particle Model (PPM) [1] offers an efficient method for simulating AFM images.



**Figure 1:** Integrating Machine Learning (ML) with PPAFM-generated datasets enables the prediction of properties such as molecular structures [2] and electrostatic force potential [3]. However, the performance of trained models on actual experimental AFM images often falls short compared to their performance on simulated images.

## Motivation

How can we enhance the performance of ML models on experimental data?



**Figure 2:** A potential solution is to alter the simulated images to more closely resemble experimental images, incorporating these modifications into the training dataset, a technique known as **Data Augmentation**. We have a large collection of simulated PPAFM images and a limited set of experimental AFM images.

## Hypothesis

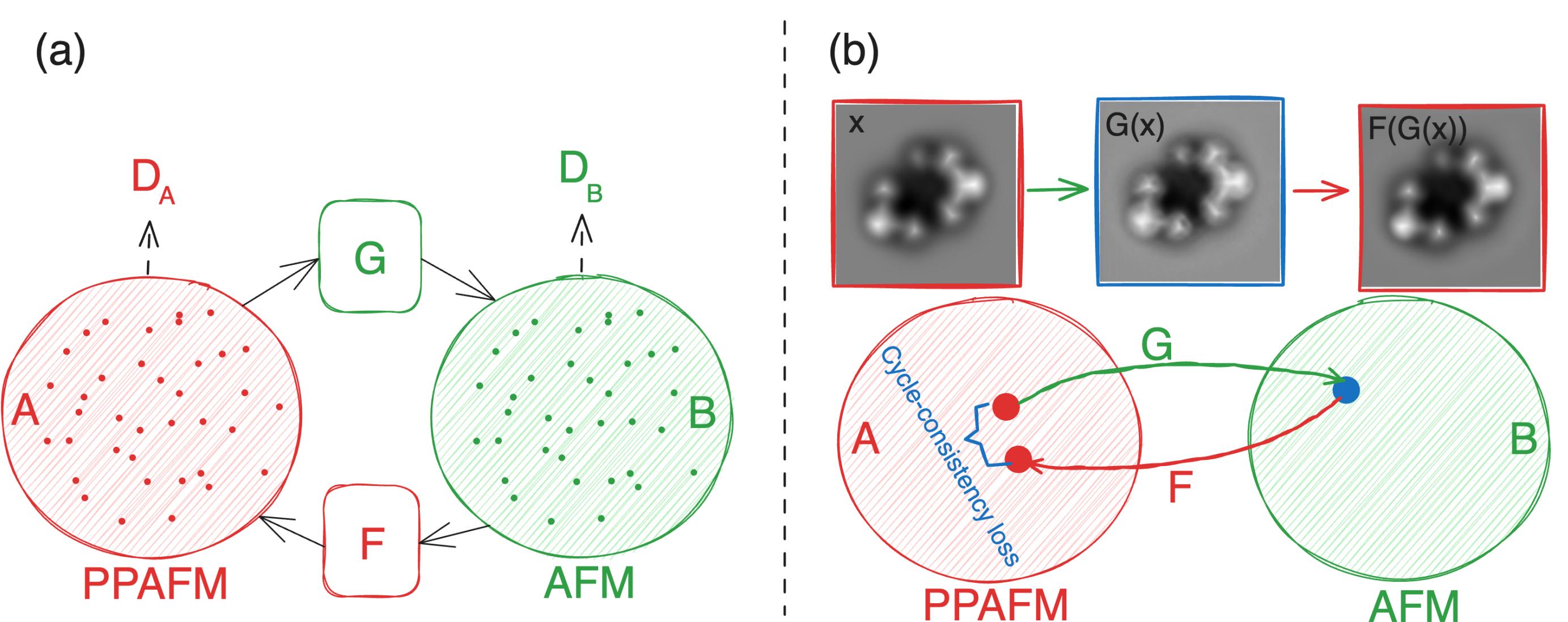
The gap between the simulation and experimental AFM images blocks the performance of machine learning models.

## References

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## Question

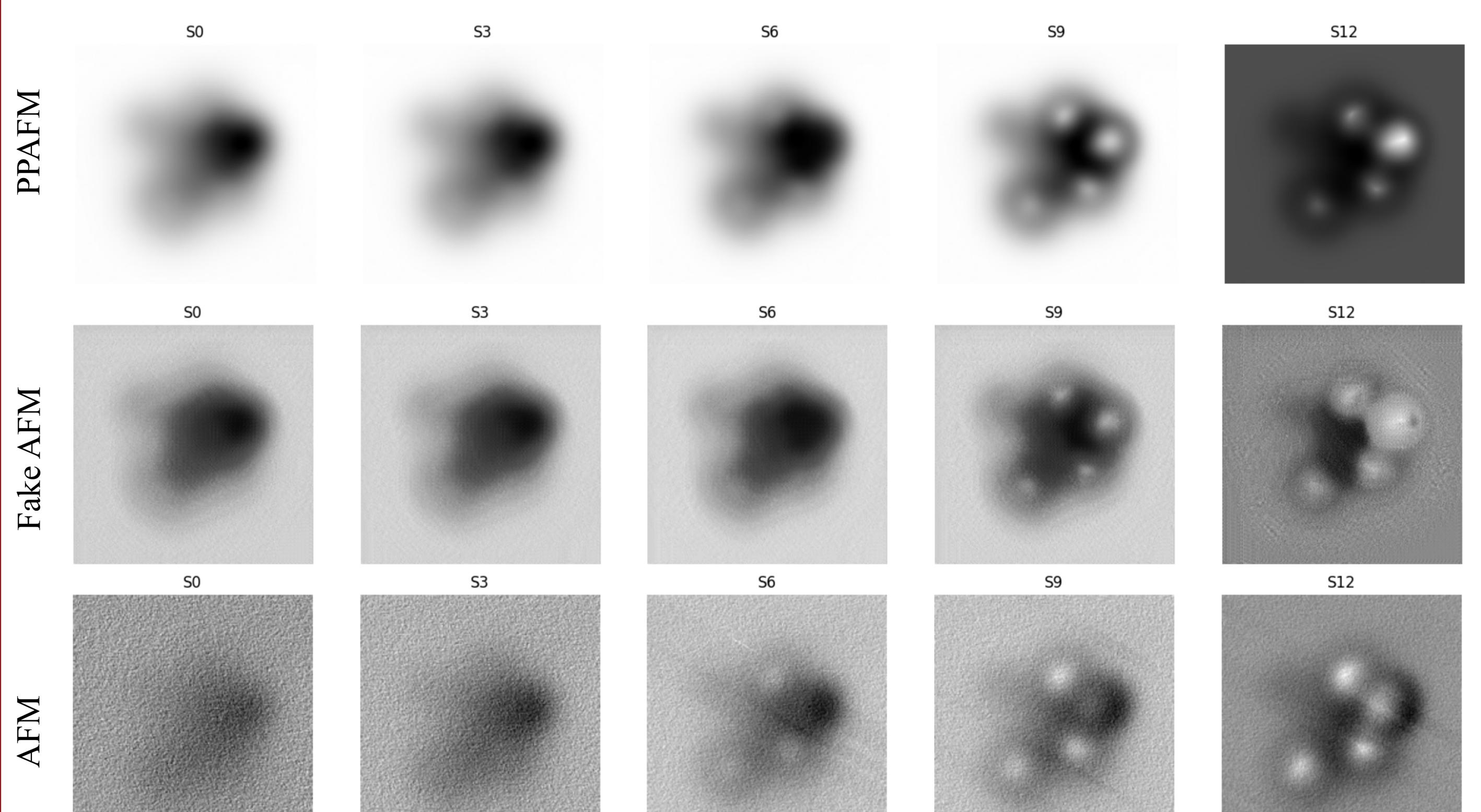
How can we produce a large number of experimental-like AFM images from simulated ones?



**Figure 3:** (a) CycleGAN [4] includes two mapping functions  $G: A \rightarrow B$  and  $F: B \rightarrow A$ , and associated adversarial discriminators  $D_A$  and  $D_B$  encourages  $G$  to translate  $A$  into outputs indistinguishable from domain  $B$ , and vice versa for  $D_A$  and  $F$ . (b) **Cycle Consistency** ensures that converting from one domain to another and back again returns to the original starting point., i.e.,  $F(G(x)) \approx x$ .

## Results

The trained generator successfully introduces experimental features, such as background shadows and noise, to the PPAFM simulation images.



**Figure 4:** Depiction of water molecules on an Au surface at different heights for PPAFM simulations, generated experimental-like AFM images, and AFM images.

## Future Directions

1. Design an automated method for assessing the quality of generated images.
2. Incorporate these generated images into the training datasets for machine learning models.

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